

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination MAK ET AL.	
		Examiner DuyVu n. Deo	Art Unit 1765	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,961,626	11-2005	Paik, Young Jeen	700/31
*	B	US-6,891,627	05-2005	Levy et al.	356/625
*	C	US-6,689,519	02-2004	Brown et al.	430/30
*	D	US-6,245,581	06-2001	Bonser et al.	438/8
*	E	US-5,926,690	07-1999	Toprac et al.	438/17
*	F	US-5,109,430	04-1992	Nishihara et al.	382/151
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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